Attornev's Docket No.: 12361-028001

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Steve Yao Art Unit: 2609

Serial No.: 10/800,406 Examiner: Shaheda Abdin

Filed : March 12, 2004

Title : MONITORING MECHANISMS FOR OPTICAL SYSTEMS

MAIL STOP AMENDMENT

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants call attention to the attached Information
Disclosure Statement and documents listed on form PTO-1449.

The documents are in the English language; hence no concise explanation is necessary per Rule 98(a)(3).

Consideration of the foregoing and enclosures plus the return of a copy of the enclosed form PTO-1449 with the Examiner's initials in the left column per MPEP 609 are earnestly solicited along with an early action on the merits.

Kindly accept this Information Disclosure Statement under Rule 97(c)(2). Please apply the rule 17(p) certification fee in the amount of \$180 to deposit account 06-1050.

Respectfully submitted,

Date: September 12, 2007 /Bing Ai/ Bing Ai

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| Substitute Form PTO-1449 (Modified) | | | | | |
|---|--|-------------------------------|------------------------|--|--|
| Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.99(b)) | | Applicant Steve Yao | | | |
| | | Filing Date March 12, 2004 | Group Art Unit 2609 | | |

| U.S. Patent Documents | | | | | | | |
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| Examiner Initial | Desig. ID | Document Number | Publication Date | Patentee | Class | Subclass | Filing Date If Appropriate |
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| Examiner Signature | Date Considered | | | | |
|---|--|--|--|--|--|
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| EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with | | | | | |
| next communication to applicant. | | | | | |
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| | EXAMINER: Initials citation considered. Draw line through citation if no | | | | |